Search Notes



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Examiner

Cho; Jennifer Y

Applicant(s)/Patent Under Reexamination

BIEHL ET AL.

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SEARCHED

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SEARCH NOTES

Search Notes	Date	Examiner
STIC Search	7/9/07	JD
East Search	7/13/07	JC
Inventor Search	7/17/07	JC

INTERFERENCE SEARCH

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